JUNO datalog decoded

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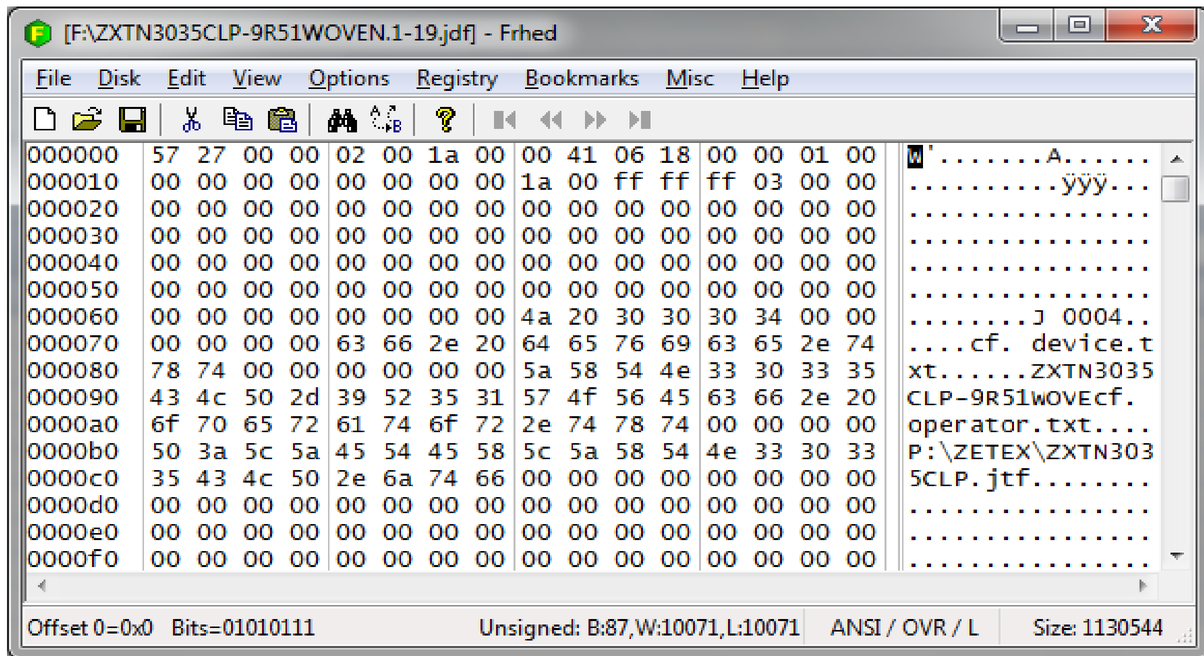
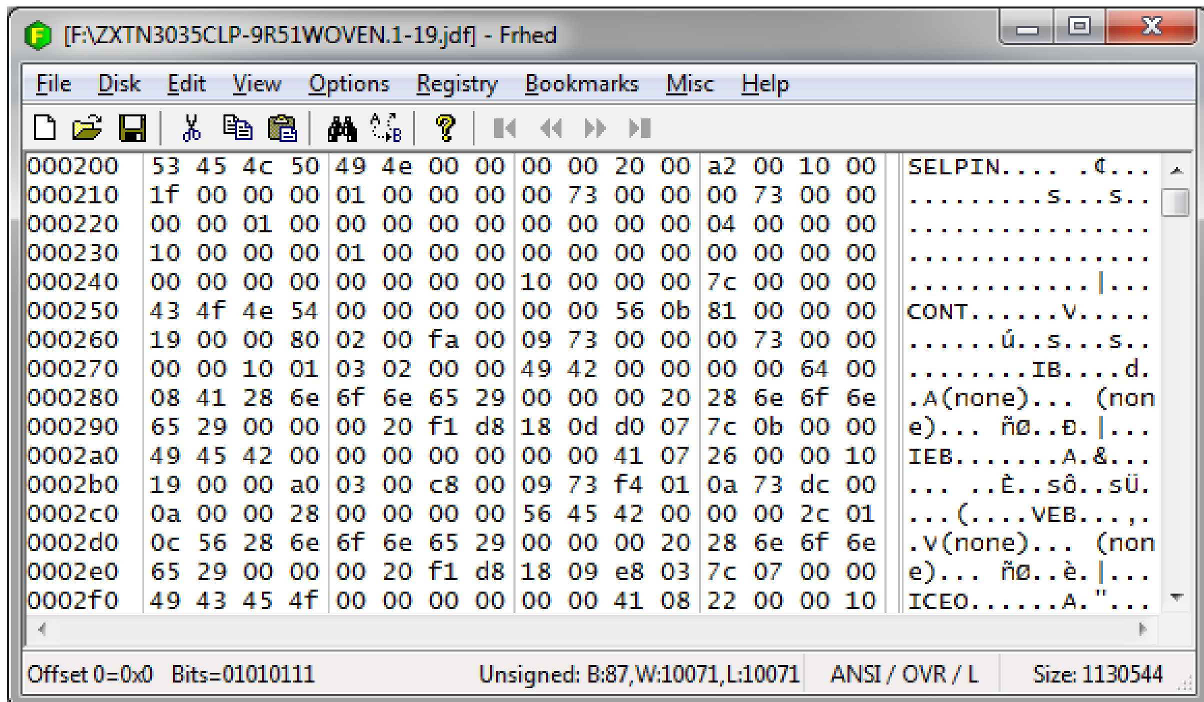
All 2 byte numbers are stored in LSB-MSB order and negative numbers in two's compliment format.

General file header Section



Memory Location	Variable
000000-000003	number of devices tested
000004	unknown
000006	number of tests in routine
000008-00001f	unknown
000068-000073	tester name
000074-000087	device name
000088-00009b	lot name
00009C-0000af	operator name
0000b0-0000c7	test routine name
0001b0-0001c7	comment

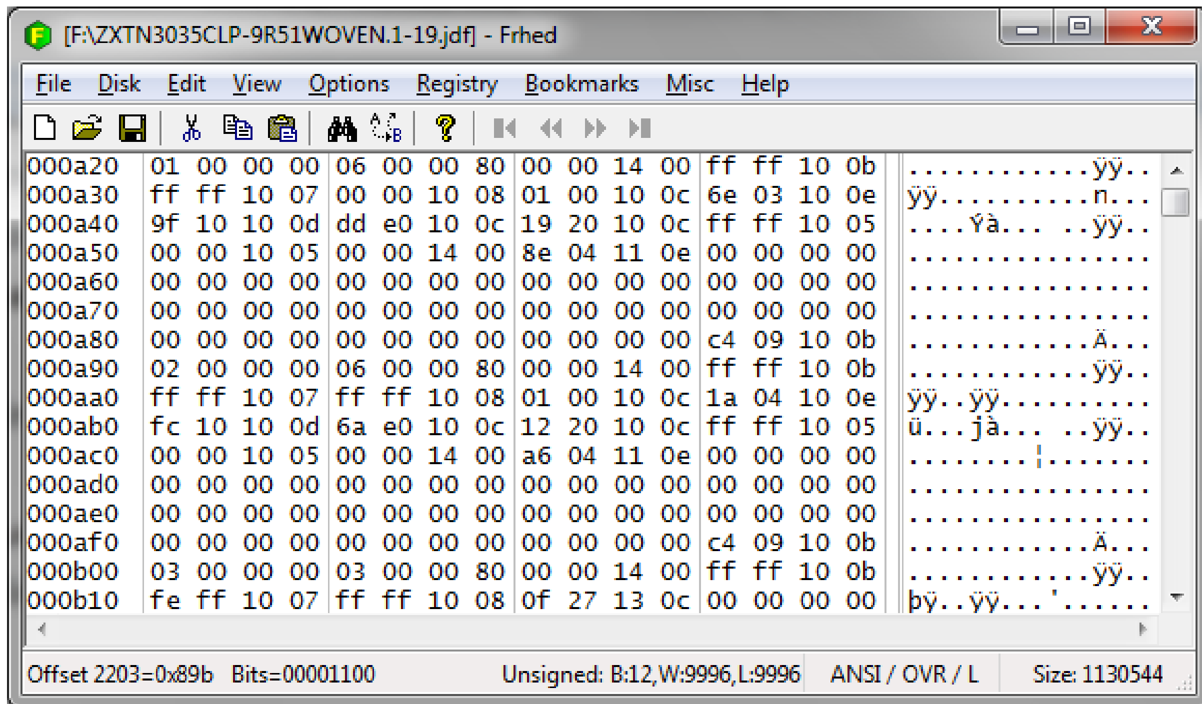
Test Header Section



Memory Location	Variable
000200	start of tester header, each test is described in 50 bytes the elements of which are listed below as an offset from the start of the test description.
00-09	test name
0a	unit of measurement (e.g. V=Volts)
0b	scaling factor (0=pico, 3=nano, 6=micro, 9=mili etc.)
0c-27	unknown
28-30	bias(condition)1
28-2d	bias name
2e-2f	bias value
30	bias scaling factor
31	bias Unit
32-3b	bias2 (see above)
3c-45	bias3 (see above)
46-47	min limit value
48	unknown
49	min limit scaling factor
4a-4b	max limit value
4c	unknown
4d	max limit scaling factor

Where a test has no limits the min and max values are shown as 00 00 but where a test has only a min or a max limit the missing limit is shown as f1 d8 (two's compliment equivalent of -9999).

<u>**Data Section**</u>



<u>Memory Location</u>	<u>Variable</u>

Starts immediately after test header section each device is described in 04 bytes for the device and 04 bytes for each test.

00-03	device number
04	bin number
07	pass/fail bit 00=pass, 80=fail
08-0b	result of test 1
08-09	value of test 1
0a	result flag 10=pass, 11=parametric fail, 13=out of range, 14= no measurement
0b	scaling factor

Repeat for remainder of tests and devices.